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<ul> <li>Function, Pinout, and Drive Compatible With FCT and F Logic</li> </ul>	Q OR SO PACKAGE (TOP VIEW)
<ul> <li>Reduced V<sub>OH</sub> (Typically = 3.3 V) Version of Equivalent FCT Functions</li> </ul>	CPAB 1 24 V <sub>CC</sub> SAB 2 23 CPBA
<ul> <li>Edge-Rate Control Circuitry for Significantly Improved Noise Characteristics</li> </ul>	GAB 3 22 SBA A1 4 21 GBA A2 5 20 B1
<ul> <li>I<sub>off</sub> Supports Partial-Power-Down Mode Operation</li> </ul>	A <sub>3</sub> [ 6 19 ] B <sub>2</sub> A <sub>4</sub> [ 7 18 ] B <sub>3</sub>
Matched Rise and Fall Times	$A_5 \begin{bmatrix} 8 & 17 \end{bmatrix} B_4$
<ul> <li>Fully Compatible With TTL Input and Output Logic Levels</li> </ul>	A <sub>6</sub> 9 16 B <sub>5</sub> A <sub>7</sub> 10 15 B <sub>6</sub> A <sub>8</sub> 11 14 B <sub>7</sub>
<ul> <li>64-mA Output Sink Current</li> <li>32-mA Output Source Current</li> </ul>	GND [ 12 13] B <sub>8</sub>
<ul> <li>Independent Register for A and B Buses</li> </ul>	

- Multiplexed Real-Time and Stored Data Transfer
- 3-State Outputs

#### description

The CY74FCT652T consists of bus transceiver circuits, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the input bus or from the internal storage registers. GAB and GBA inputs control the transceiver functions. Select-control (SAB and SBA) inputs select either real-time or stored-data transfer. The circuitry used for select control eliminates the typical decoding glitch that occurs in a multiplexer during the transition between stored and real-time data. A low input level selects real-time data, and a high input level selects stored data.

Data on the A or B data bus, or both, can be stored in the internal D-type flip-flops by low-to-high transitions of the appropriate clock (CPAB or CPBA) inputs, regardless of the select or enable levels of the control pins. When SAB and SBA are in the real-time transfer mode, it also is possible to store data without using the internal D-type flip-flops by simultaneously enabling GAB and GBA. In this configuration, each output reinforces its input. Thus, when all other data sources to the two sets of bus lines are at high impedance, each set of bus lines remains at its last state.

This device is fully specified for partial-power-down applications using I<sub>off</sub>. The I<sub>off</sub> circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.



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TA	PAC	KAGE <sup>†</sup>	SPEED (ns)	ORDERABLE PART NUMBER	TOP-SIDE MARKING						
	QSOP – Q	Tape and reel	5.4	CY74FCT652CTQCT	FCT652C						
	SOIC – SO	Tube	5.4	CY74FCT652CTSOC	FCT652C						
		Tape and reel	5.4	CY74FCT652CTSOCT	FC1052C						
–40°C to 85°C	QSOP – Q	Tape and reel	6.3	CY74FCT652ATQCT	FCT652A						
	SOIC – SO	Tube	6.3	CY74FCT652ATSOC	FCT652A						
	3010 - 30	Tape and reel	6.3	CY74FCT652ATSOCT	FCT052A						
	QSOP – Q	Tape and reel	9	CY74FCT652TQCT	FCT652						

#### **ORDERING INFORMATION**

<sup>†</sup> Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

					1.011			
		INP	UTS			DAT	a I/o	OPERATION OR
GAB	GBA	CPAB	СРВА	SAB	SBA	A <sub>1</sub> –A <sub>8</sub>	В <sub>1</sub> –В <sub>8</sub>	FUNCTION
L	Н	H or L	H or L	Х	Х	Input	Input	Isolation
L	Н	$\uparrow$	$\uparrow$	Х	х	Input	Input	Store A and B data
Х	Н	$\uparrow$	H or L	Х	Х	Input	Unspecified§	Store A, hold B
н	Н	$\uparrow$	$\uparrow$	Х‡	х	Input	Output	Store A in both registers
L	Х	H or L	$\uparrow$	Х	Х	Unspecified§	Input	Hold A, store B
L	L	$\uparrow$	Ŷ	Х	х‡	Output	Input	Store B in both registers
L	L	Х	Х	Х	L	Output	Input	Real-time B data to A bus
L	L	Х	H or L	Х	н	Output	Input	Stored B data to A bus
н	Н	Х	Х	L	Х	Input	Output	Real-time A data to B bus
н	н	H or L	Х	Н	Х	Input	Output	Stored A data to B bus
н	L	H or L	H or L	Н	Н	Output	Output	Stored A data to B bus and Stored B data to A bus

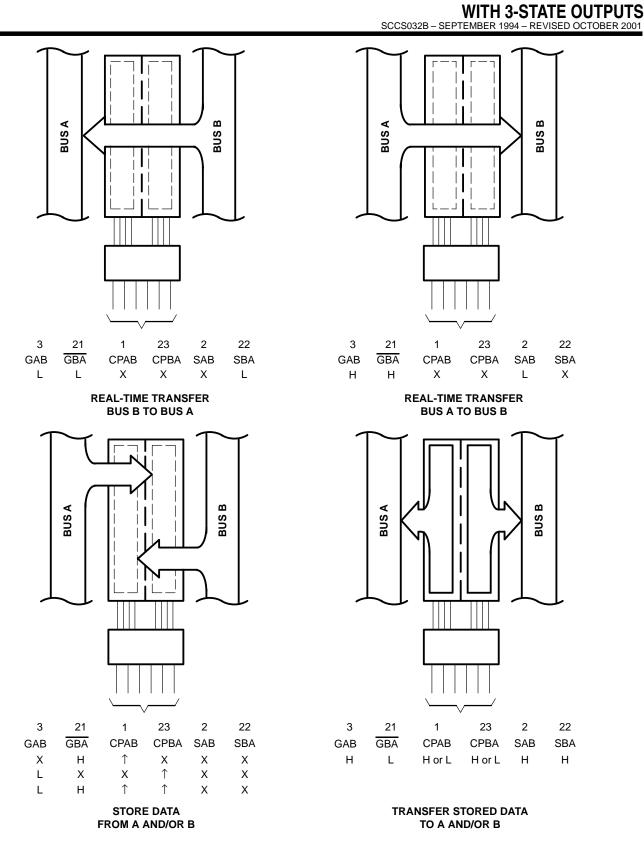
#### FUNCTION TABLE

H = High logic level, L = Low logic level, X = Don't care,  $\uparrow$  = Low-to-high transition

<sup>‡</sup> Select control = L: clocks can occur simultaneously. Select control = H: clocks must be staggered in order to load both registers.

\$ The data output functions can be enabled or disabled by various signals at the GAB and GBA inputs. Data input functions always are enabled, i.e., data at the bus pins are stored on every low-to-high transition of the clock inputs.







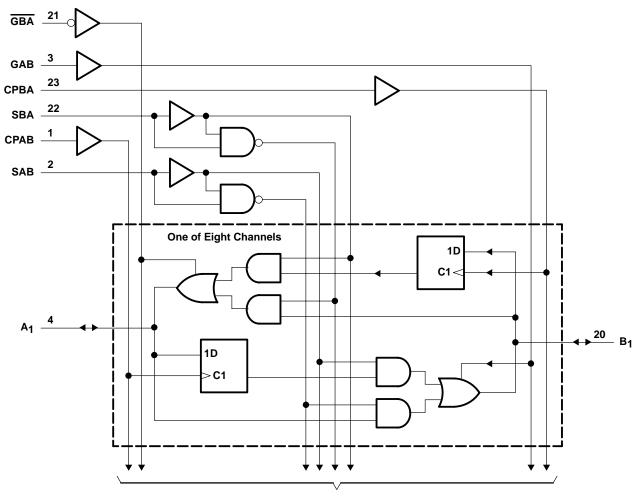


**CY74FCT652T** 

**8-BIT REGISTERED TRANSCEIVER** 

#### CY74FCT652T 8-BIT REGISTERED TRANSCEIVER WITH 3-STATE OUTPUTS SCCS032B – SEPTEMBER 1994 – REVISED OCTOBER 2001

#### logic diagram (positive logic)



**To Seven Other Channels** 



## **CY74FCT652T 8-BIT REGISTERED TRANSCEIVER** WITH 3-STATE OUTPUTS SCCS032B – SEPTEMBER 1994 – REVISED OCTOBER 2001

#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range to ground potential	0.5	V to 7 V
DC input voltage range	0.5	V to 7 V
DC output voltage range	0.5	V to 7 V
DC output current (maximum sink current/pin)		120 mA
Package thermal impedance, $\theta_{JA}$ (see Note 1): Q package		61°C/W
SO package		46°C/W
Ambient temperature range with power applied, T <sub>A</sub>	–65°C t	o 135°C
Storage temperature range, T <sub>stg</sub>	–65°C t	o 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The package thermal impedance is calculated in accordance with JESD 51-7.

#### recommended operating conditions (see Note 2)

		MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.75	5	5.25	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			0.8	V
ЮН	High-level output current			-32	mA
IOL	Low-level output current			64	mA
TA	Operating free-air temperature	-40		85	°C

NOTE 2: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation.



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## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	5	MIN	түр†	MAX	UNI
VIK	V <sub>CC</sub> = 4.75 V,	I <sub>IN</sub> = -18 mA			-0.7	-1.2	V
		I <sub>OH</sub> = -32 mA		2			
VOH	V <sub>CC</sub> = 4.75 V	I <sub>OH</sub> = -15 mA		2.4	3.3		V
VOL	V <sub>CC</sub> = 4.75 V,	I <sub>OL</sub> = 64 mA			0.3	0.55	V
V <sub>hys</sub>	All inputs				0.2		V
ų	V <sub>CC</sub> = 5.25 V,	V <sub>IN</sub> = V <sub>CC</sub>				5	μA
Iн	V <sub>CC</sub> = 5.25 V,	V <sub>IN</sub> = 2.7 V				±1	μA
ΙL	V <sub>CC</sub> = 5.25 V,	V <sub>IN</sub> = 0.5 V				±1	μA
IOZH	V <sub>CC</sub> = 5.25 V,	V <sub>OUT</sub> = 2.7 V				10	μA
IOZL	V <sub>CC</sub> = 5.25 V,	V <sub>OUT</sub> = 0.5 V				-10	μA
I <sub>OS</sub> ‡	V <sub>CC</sub> = 5.25 V,	V <sub>OUT</sub> = 0 V		-60	-120	-225	m
l <sub>off</sub>	$V_{CC} = 0 V,$	V <sub>OUT</sub> = 4.5 V				±1	μA
ICC	V <sub>CC</sub> = 5.25 V,	$V_{IN} \leq 0.2 V$ ,	$V_{IN} \ge V_{CC} - 0.2 V$		0.1	0.2	mA
ΔICC	V <sub>CC</sub> = 5.25 V, V <sub>IN</sub> = 3	.4 V§, $f_1 = 0$ , Outputs op	en		0.5	2	m
ICCD		out switching at 50% duty / <sub>IN</sub> ≤ 0.2 V or V <sub>IN</sub> ≥ V <sub>CC</sub>			0.06	0.12	m∕ M⊦
	$V_{CC} = 5.25 V,$ f <sub>0</sub> = 10 MHz,	One bit switching at f <sub>1</sub> = 5 MHz	$\begin{array}{l} V_{IN} \leq 0.2 \ V \ or \\ V_{IN} \geq V_{CC} - 0.2 \ V \end{array}$		0.7	1.4	
ı#	Outputs open,	at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		1.2	3.4	
5	$GAB = \overline{GBA} = GND,$ SAB = CPAB = GND,	Eight bits switching at f <sub>1</sub> = 5 MHz	$\begin{array}{l} V_{IN} \leq 0.2 \ V \ or \\ V_{IN} \geq V_{CC} - 0.2 \ V \end{array}$		2.8	5.6ll	m/
	$SBA = V_{CC}$	at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		5.1	14.6ll	
Ci					5	10	pF
Co					9	12	pF

<sup>†</sup> Typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

\* Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample-and-hold techniques are preferable to minimize internal chip heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output can raise the chip temperature well above normal and cause invalid readings in other parametric tests. In any sequence of parameter tests, IOS tests should be performed last.

§ Per TTL-driven input  $(V_{IN} = 3.4 \text{ V})$ ; all other inputs at V<sub>CC</sub> or GND

This parameter is derived for use in total power-supply calculations.

<sup>#</sup> IC = ICC +  $\Delta$ ICC × D<sub>H</sub> × N<sub>T</sub> + I<sub>CCD</sub> (f<sub>0</sub>/2 + f<sub>1</sub> × N<sub>1</sub>)

Where:

IC = Total supply current

I<sub>CC</sub> = Power-supply current with CMOS input levels

 $\Delta I_{CC}$  = Power-supply current for a TTL high input (VIN = 3.4 V)

 $D_H$  = Duty cycle for TTL inputs high

 $N_T$  = Number of TTL inputs at  $D_H$ 

I<sub>CCD</sub> = Dynamic current caused by an input transition pair (HLH or LHL)

 $f_0$  = Clock frequency for registered devices, otherwise zero

f<sub>1</sub> = Input signal frequency

N<sub>1</sub> = Number of inputs changing at f<sub>1</sub>

All currents are in milliamperes and all frequencies are in megahertz.

Il Values for these conditions are examples of the ICC formula.



#### CY74FCT652T 8-BIT REGISTERED TRANSCEIVER WITH 3-STATE OUTPUTS SCCS032B – SEPTEMBER 1994 – REVISED OCTOBER 2001

# timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 2)

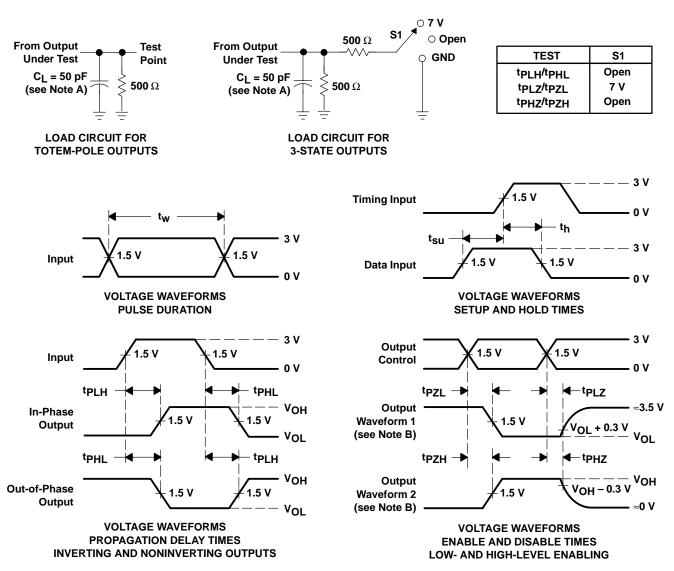
						652AT	CY74FCT	652CT	UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT	
tw	Pulse duration, clock high or low		6		5		5		ns
t <sub>su</sub>	Setup time, before CPAB $\uparrow$ or CPBA $\uparrow$	A or B	4		2		2		ns
th	Hold time, after CPAB $\uparrow$ or CPBA $\uparrow$	A or B	2		1.5		1.5		ns

#### switching characteristics over operating free-air temperature range (see Figure 2)

-		-				-			
PARAMETER	FROM	то	CY74FC	CT652T	CY74FC	F652AT	CY74FCT652CT		UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	MIN	MAX	
<sup>t</sup> PLH	A or B	B or A	1.5	9	1.5	6.3	1.5	5.4	ns
<sup>t</sup> PHL	AUB	BUIA	1.5	9	1.5	6.3	1.5	5.4	115
<sup>t</sup> PZH	GAB or GBA	A or B	1.5	14	1.5	9.8	1.5	7.8	ns
<sup>t</sup> PZL	GAD OF GDA	AUB	1.5	14	1.5	9.8	1.5	7.8	115
<sup>t</sup> PHZ	GAB or GBA	A or B	1.5	9	1.5	6.3	1.5	6.3	ns
<sup>t</sup> PLZ	GAD OF GDA	AOIB	1.5	9	1.5	6.3	1.5	6.3	115
<sup>t</sup> PLH	CPAB or CPBA	A or B	1.5	9	1.5	6.3	1.5	5.7	ns
<sup>t</sup> PHL		AUB	1.5	9	1.5	6.3	1.5	5.7	115
<sup>t</sup> PLH	SBA or SAB	A or B	1.5	11	1.5	7.7	1.5	6.2	20
<sup>t</sup> PHL	SBA UI SAB	AUB	1.5	11	1.5	7.7	1.5	6.2	ns



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 C. The outputs are measured one at a time with one input transition per measurement.

Figure 2. Load Circuit and Voltage Waveforms





6-Feb-2020

#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	•	Pins	0	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
CY74FCT652ATQCT	ACTIVE	SSOP	DBQ	24	2500	Green (RoHS & no Sb/Br)	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT652A	Samples
CY74FCT652ATSOC	ACTIVE	SOIC	DW	24	25	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT652A	Samples
CY74FCT652ATSOCT	ACTIVE	SOIC	DW	24	2000	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT652A	Samples
CY74FCT652CTQCT	ACTIVE	SSOP	DBQ	24	2500	Green (RoHS & no Sb/Br)	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT652C	Samples
CY74FCT652CTSOCT	ACTIVE	SOIC	DW	24	2000	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT652C	Samples
CY74FCT652TQCT	ACTIVE	SSOP	DBQ	24	2500	Green (RoHS & no Sb/Br)	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT652	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

<sup>(5)</sup> Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.



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<sup>(6)</sup> Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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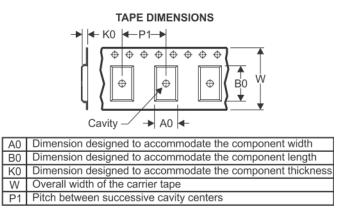
## PACKAGE MATERIALS INFORMATION

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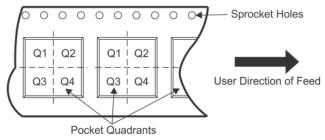
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#### TAPE AND REEL INFORMATION





#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



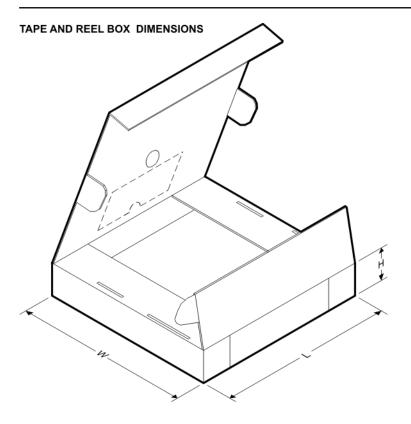
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CY74FCT652ATQCT	SSOP	DBQ	24	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CY74FCT652ATSOCT	SOIC	DW	24	2000	330.0	24.4	10.75	15.7	2.7	12.0	24.0	Q1
CY74FCT652CTQCT	SSOP	DBQ	24	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CY74FCT652CTSOCT	SOIC	DW	24	2000	330.0	24.4	10.75	15.7	2.7	12.0	24.0	Q1
CY74FCT652TQCT	SSOP	DBQ	24	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1

TEXAS INSTRUMENTS

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## PACKAGE MATERIALS INFORMATION

14-Feb-2019

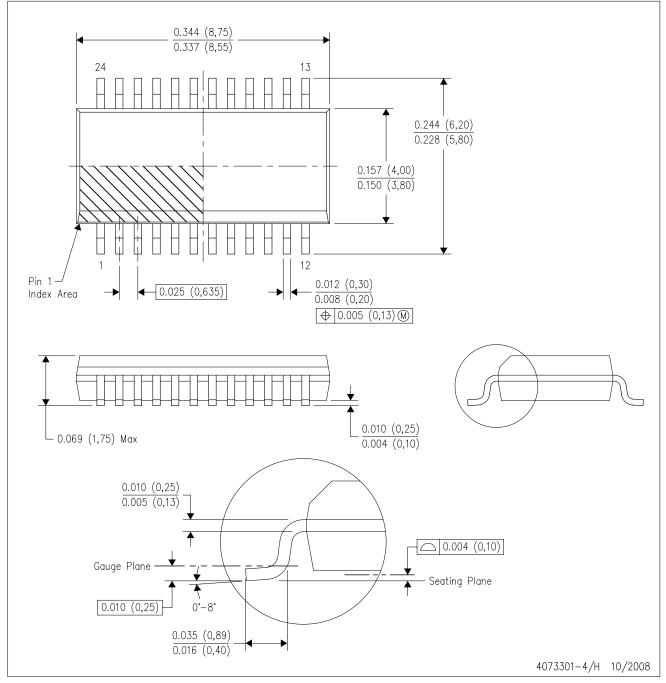


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CY74FCT652ATQCT	SSOP	DBQ	24	2500	367.0	367.0	38.0
CY74FCT652ATSOCT	SOIC	DW	24	2000	350.0	350.0	43.0
CY74FCT652CTQCT	SSOP	DBQ	24	2500	367.0	367.0	38.0
CY74FCT652CTSOCT	SOIC	DW	24	2000	350.0	350.0	43.0
CY74FCT652TQCT	SSOP	DBQ	24	2500	367.0	367.0	38.0

DBQ (R-PDSO-G24)

PLASTIC SMALL-OUTLINE PACKAGE



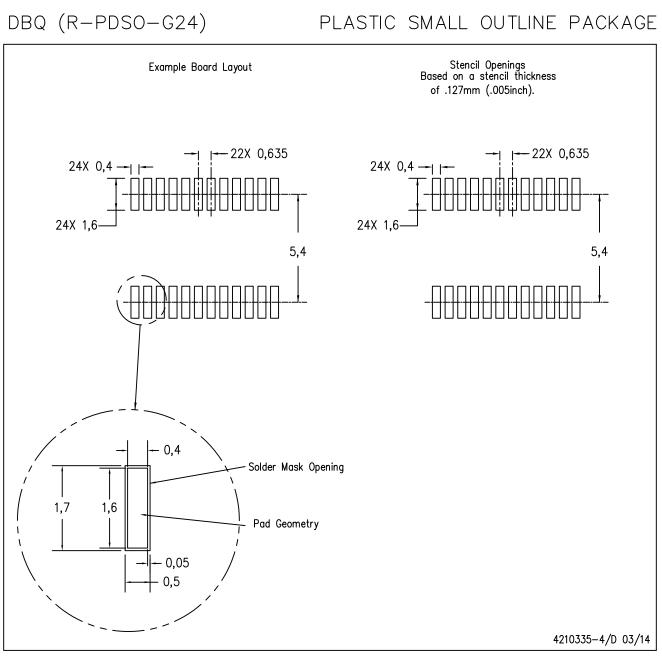
NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15) per side.

D. Falls within JEDEC MO-137 variation AE.





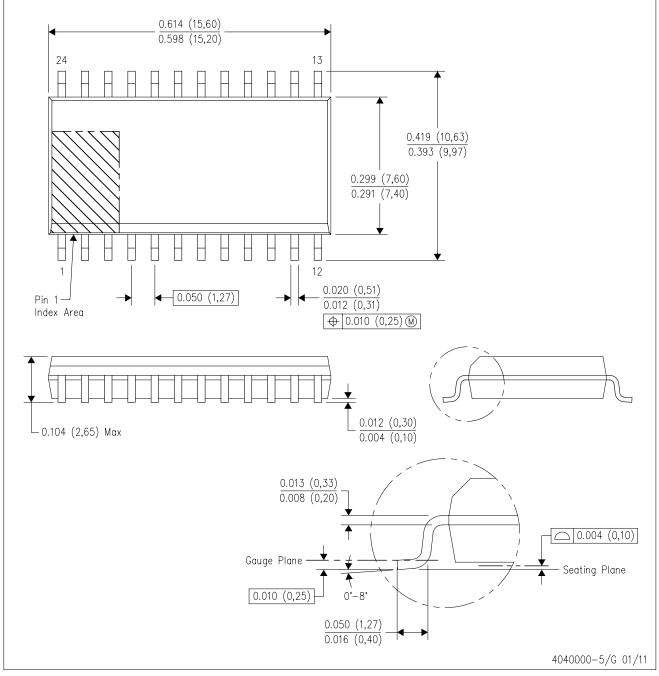
NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.



DW (R-PDSO-G24)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-013 variation AD.



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